

<b>Notice of References Cited</b>	Application/Control No. 10/713,794	Applicant(s)/Patent Under Reexamination KARR ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0099303 A1	05-2003	Birru et al.	375/265
*	B	US-5,949,822 A	09-1999	Hancharik, David J.	375/242
*	C	US-5,442,646 A	08-1995	Chadwick et al.	714/795
*	D	US-2005/0052571 A1	03-2005	Ghosh, Monisha	348/426.1
*	E	US-2003/0105913 A1	06-2003	Lee, Jae-Hong	711/5
*	F	US-6,671,284 B1	12-2003	Yonge et al.	370/462
*	G	US-2005/0201368 A1	09-2005	Periyalwar et al.	370/356
*	H	US-2002/0090938 A1	07-2002	Dharia et al.	455/422
*	I	US-6,567,471 B1	05-2003	Yoshinari, Hiromi	375/240.26
*	J	US-5,694,404	12-1997	Huang, Wei-Hung	714/751
*	K	US-4,692,894	09-1987	Bemis, Gerald L.	710/57
*	L	US-5,548,814 A	08-1996	Lorang et al.	370/310
*	M	US-6,101,168	08-2000	Chen et al.	370/228

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 95/22233	08-1995	PCT	Bessette	H04Q 11/04
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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